IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s):

Mehdi Vaez-Iravani et al.

Assignee:

KLA-Tencor Corporation

Title:

Sample Inspection System

Application No.:

10/627,402

Filing Date:

July 24, 2003

Examiner:

Not yet assigned

Group Art Unit:

2877

Docket No.:

TNCR.152US7

Conf. No.:

2861

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant calls the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a representation that a search has been made (other than as indicated by any cited document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

This application has a filing date after June 30, 2003. Copies of the U.S. Patent(s) and U.S. Published Patent Application(s) documents listed on the accompanying Form PTO-1449 are not enclosed, or were previously submitted in Application Nos. 10/033,069; 09/746,141; and 08/933,771, from which this Application claims an earlier effective filing date.

This information disclosure statement is submitted under 37 C.F.R. § 1.97(b) and consequently no fee should be required. The Commissioner is authorized, however, to charge any fee that may be required, or to credit any overpayment, against Deposit Account No. 502664. This form is being submitted in duplicate.

Certificate of Mailing Under 37 CFR 1.8

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope address to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on August 18, 2004.

Franklin Dyer

Respectfully submitted,

Reg. No. 29,545

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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.